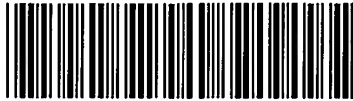


**Search Notes**

Application/Control No.

10/786,799

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	313		
	314		
	316		
	274-281		
327	539		
	540		
323	317	3/17/2006	JH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR